



# MP87L75

Low Voltage CMOS  
8-Bit High Speed  
Analog-to-Digital Converter

## FEATURES

- 3.3 Volt Operation
- 8-Bit Resolution
- Small 20 Pin SOIC, PDIP & SSOP Packages
- DNL =  $\pm 1/2$  LSB, INL =  $\pm 1$  LSB (typ)
- Internal S/H Function
- $V_{IN}$  DC Range: 0 V to  $V_{DD}$
- $V_{REF}$  DC Range: 1 V to  $V_{DD}$
- Low Power: 20 mW typ. (excluding reference)
- Latch-Up Free

## APPLICATIONS

- Digital Radio
- Cellular Telephones
- CCD's and Scanners
- Hand Held and Battery Powered Data Acquisition

## GENERAL DESCRIPTION

The MP87L75 is an 8-bit Analog-to-Digital Converter in a small 20 pin SOIC package that operates at 3.3 V. Designed using an advanced CMOS process, this part offers excellent performance, low power consumption and latch-up free operation.

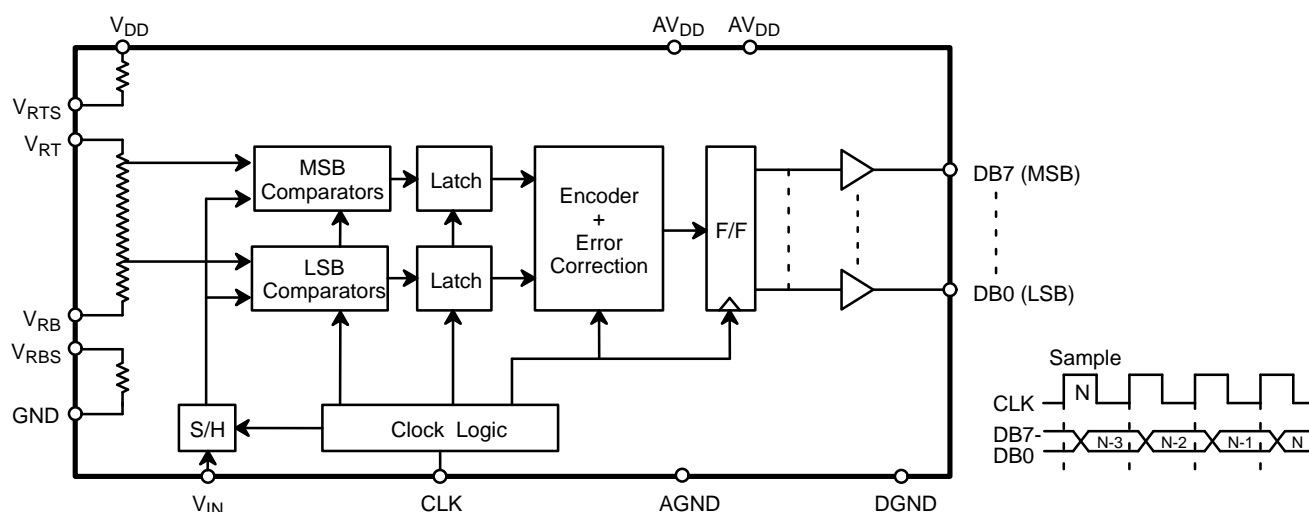
This device uses a two-step flash architecture to maintain low power consumption at high conversion rates. The input circuitry of the MP87L75 includes an on-chip S/H function and allows the user to digitize analog input signals between GND and  $V_{DD}$ . Careful design and chip layout have achieved a low analog input capacitance. This reduces "kickback" and eases the requirements of the buffer/amplifier used to drive the MP87L75.

The designer can choose the internally generated reference voltages by connecting  $V_{RB}$  to  $V_{RBS}$  and  $V_{RT}$  to  $V_{RTS}$ , or provide external reference voltages to the  $V_{RB}$  and  $V_{RT}$  pins. The internal reference generates 0.4 V at  $V_{RB}$  and 1.72 V at  $V_{RT}$ . Providing external reference voltages allows easy interface to any input signal range between GND and  $V_{DD}$ . This also allows the system to adjust these voltages to cancel zero scale and full scale errors, or to change the input range as needed.

The device operates from a single +3.3 V supply  $\pm 10\%$ . Power consumption is 20 mW at FS = 10 MHz.

Specified for operation over the commercial / industrial ( $-40$  to  $+85^{\circ}\text{C}$ ) temperature range, the MP87L75 is available in Plastic dual-in-line (PDIP), Surface Mount (SOIC), and Shrunk small outline (SSOP) packages.

## SIMPLIFIED BLOCK AND TIMING DIAGRAM

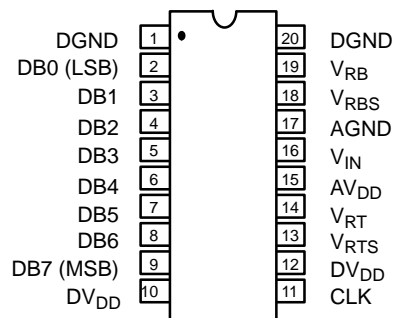


## ORDERING INFORMATION

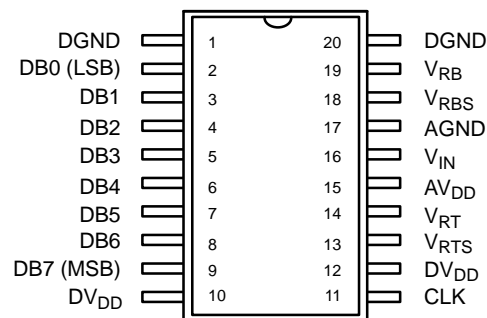
Package Type	Temperature Range	Part No.	DNL (LSB)	INL (LSB)
SOIC	–40 to +85°C	MP87L75AS	$\pm 1/2$	1 1/2
SSOP	–40 to +85°C	MP87L75AQ	$\pm 1/2$	1 1/2
PDIP	–40 to +85°C	MP87L75AN	$\pm 1/2$	1 1/2

## PIN CONFIGURATIONS

See Packaging Section for  
Package Dimensions



**20 Pin PDIP (0.300")  
N20**



**20 Pin SOIC (Jedec, 0.300") – S20  
20 Pin SSOP – A20**

## PIN OUT DEFINITIONS

PIN NO.	NAME	DESCRIPTION
1	DGND	Digital Ground
2	DB0	Data Output Bit 0 (LSB)
3	DB1	Data Output Bit 1
4	DB2	Data Output Bit 2
5	DB3	Data Output Bit 3
6	DB4	Data Output Bit 4
7	DB5	Data Output Bit 5
8	DB6	Data Output Bit 6
9	DB7	Data Output Bit 7 (MSB)
10	DVDD	Digital Power Supply

PIN NO.	NAME	DESCRIPTION
11	CLK	Sample Clock
12	DVDD	Digital Power Supply
13	VRTS	Internal Top Ladder Bias
14	VRT	Top Reference
15	AVDD	Analog Power Supply
16	VIN	Analog Input
17	AGND	Analog Ground
18	VRBS	Internal Bottom Ladder Bias
19	VRB	Bottom Reference
20	DGND	Digital Ground

## ELECTRICAL CHARACTERISTICS TABLE

Unless Otherwise Specified:  $AV_{DD} = DV_{DD} = 3.3\text{ V}$ ,  $FS = 6\text{ MHz}$  (50% Duty Cycle),  
 $V_{RT} = 2.5\text{ V}$ ,  $V_{RB} = 0.5\text{ V}$ ,  $T_A = 25^\circ\text{C}$

Parameter	Symbol	Min	25°C Typ	Max	Units	Test Conditions/Comments
<b>KEY FEATURES</b>						
Resolution Sampling Rate	FS	8		10	Bits MHz	
<b>ACCURACY (A Grade)<sup>1</sup></b>						
Differential Non-Linearity Integral Non-Linearity	DNL INL			±1/2 1 1/2	LSB LSB	Best Fit Line (Min INL – Max INL)/2
<b>REFERENCE VOLTAGES</b>						
Differential Ref. Voltage <sup>3</sup> Ladder Resistance Ladder Temp. Coefficient Self Bias 1 Short V <sub>RB</sub> and V <sub>RBS</sub> Short V <sub>RT</sub> and V <sub>RTS</sub> Self Bias 2 V <sub>RB</sub> = AGND, Short V <sub>RT</sub> and V <sub>RTS</sub>	V <sub>REF</sub> R <sub>L</sub> R <sub>TCO</sub>  V <sub>RB</sub> V <sub>RT</sub> -V <sub>RB</sub>  V <sub>RT</sub>	1.0	 350 2000  0.4 1.32  1.52	A <sub>VDD</sub>	V Ω ppm/°C  V V  V	V <sub>REF</sub> = V <sub>RT</sub> – V <sub>RB</sub>
<b>ANALOG INPUT</b>						
Input Bandwidth (–1 dB) <sup>4</sup> Input Voltage Range Input Capacitance <sup>5</sup> Aperture Delay	BW V <sub>IN</sub> C <sub>IN</sub> t <sub>AP</sub>	 V <sub>RB</sub>	5  16 30	 V <sub>RT</sub>	MHz V pF ns	
<b>DIGITAL INPUTS</b>						
Logical “1” Voltage Logical “0” Voltage DC Leakage Currents <sup>6</sup> CLK Input Capacitance Clock Timing ( <i>See Figure 1.</i> ) <sup>7</sup> Clock Period High Pulse Width Low Pulse Width	V <sub>IH</sub> V <sub>IL</sub> I <sub>IN</sub>   1/FS t <sub>PWH</sub> t <sub>PWL</sub>	2.5	  5 5  100 50 50	0.5	V V  μA pF  ns ns ns	V <sub>IN</sub> =DGND to DV <sub>DD</sub>
<b>DIGITAL OUTPUTS</b>						
Logical “1” Voltage Logical “0” Voltage Data Valid Delay	V <sub>OH</sub> V <sub>OL</sub> t <sub>DL</sub>	2.5	 30	0.5	V V ns	C <sub>OUT</sub> =15 pF  I <sub>LOAD</sub> = 1 mA I <sub>LOAD</sub> = 1 mA

## ELECTRICAL CHARACTERISTICS TABLE (CONT'D)

Description	Symbol	25°C			Units	Conditions
		Min	Typ	Max		
POWER SUPPLIES						
Operating Voltage (AV <sub>DD</sub> , DV <sub>DD</sub> )	V <sub>DD</sub>	3	3.3	3.6	V	Does not include ref. current
Current	I <sub>DD</sub>		6	12	mA	

## NOTES

- <sup>1</sup> Tester measures code transitions by dithering the voltage of the analog input (V<sub>IN</sub>). The difference between the measured and the ideal code width (V<sub>REF</sub>/256) is the DNL error (*Figure 2*). The INL error is the maximum distance (in LSBs) from the best fit line to any transition voltage (*Figure 3*). Accuracy is a function of the sampling rate (FS).
- <sup>2</sup> Guaranteed. Not tested.
- <sup>3</sup> Specified values guarantee functionality. Refer to other parameters for accuracy.
- <sup>4</sup> -1 dB bandwidth is a measure of performance of the A/D input stage (S/H + amplifier). Refer to other parameters for accuracy within the specified bandwidth.
- <sup>5</sup> See V<sub>IN</sub> input equivalent circuit (*Figure 4*). Switched capacitor analog input requires driver with low output resistance.
- <sup>6</sup> All inputs have diodes to V<sub>DD</sub> and GND. Input DC currents will not exceed specified limits for any input voltage between GND and V<sub>DD</sub>.
- <sup>7</sup> t<sub>R</sub>, t<sub>F</sub> should be limited to >5 ns for best results.
- <sup>8</sup> AGND & DGND pins are connected through the silicon substrate. Connect together at the package and to the analog ground plane.

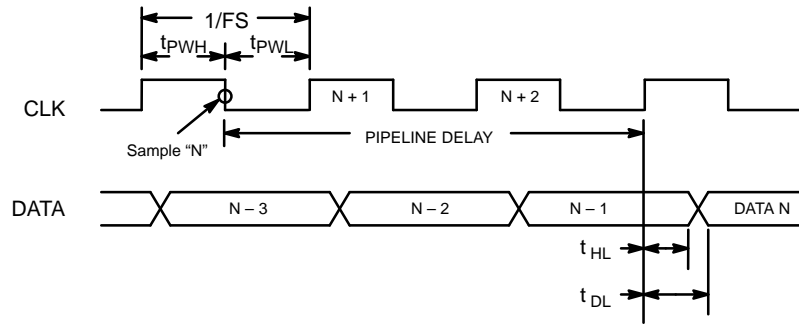
Specifications are subject to change without notice

ABSOLUTE MAXIMUM RATINGS (TA = +25°C unless otherwise noted)<sup>1, 2, 3</sup>

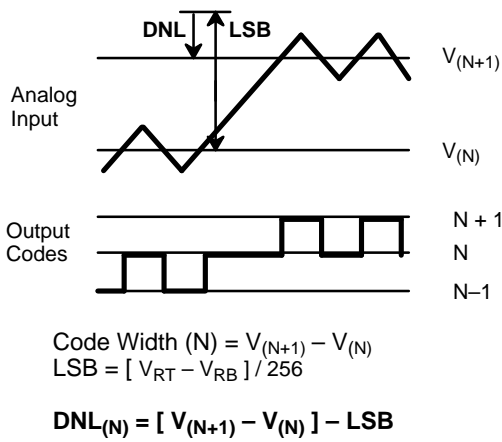
V <sub>DD</sub> to GND	5.5 V	Storage Temperature	-65 to +150°C
V <sub>RT</sub> & V <sub>RB</sub>	V <sub>DD</sub> +0.5 to GND -0.5 V	Lead Temperature (Soldering 10 seconds)	+300°C
V <sub>IN</sub>	V <sub>DD</sub> +0.5 to GND -0.5 V	Package Power Dissipation Rating @ 75°C	
All Inputs	V <sub>DD</sub> +0.5 to GND -0.5 V	SOIC, SSOP, PDIP	700 mW
All Outputs	V <sub>DD</sub> +0.5 to GND -0.5 V	Derates above 75°C	9mW/°C

## NOTES:

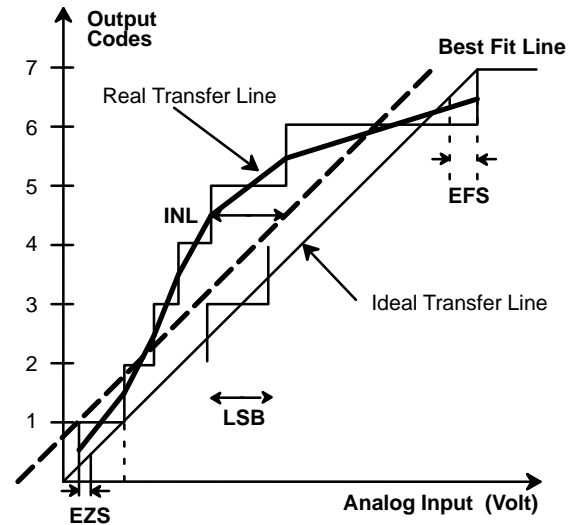
- <sup>1</sup> Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.
- <sup>2</sup> Any input pin which can see a value outside the absolute maximum ratings should be protected by Schottky diode clamps (HP5082-2835) from input pin to the supplies. All inputs have protection diodes which will protect the device from short transients outside the supplies of less than 100mA for less than 100μs.
- <sup>3</sup> V<sub>DD</sub> refers to AV<sub>DD</sub> and DV<sub>DD</sub>. GND refers to AGND and DGND.



**Figure 1. MP87L75 Timing Diagram**



**Figure 2. DNL Measurement**



**Figure 3. INL Error Calculation**

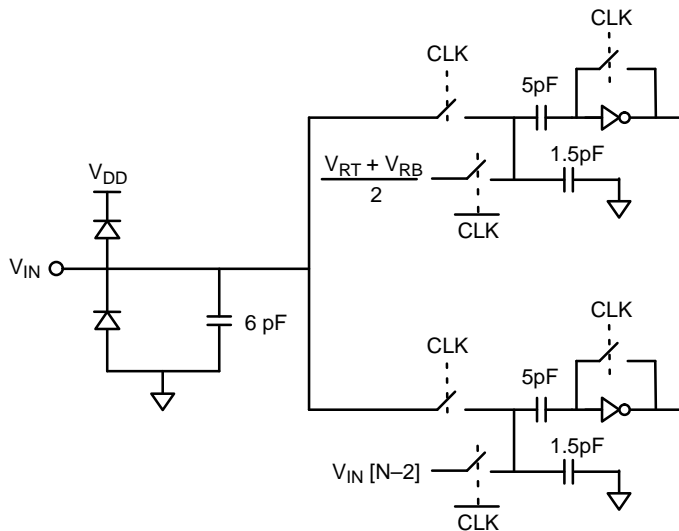


Figure 4. Equivalent Input Circuit

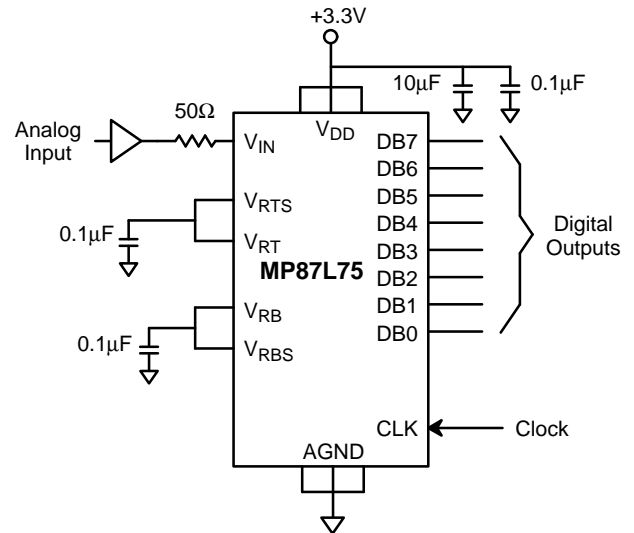


Figure 5. Typical Circuit Connections

## APPLICATION NOTES

Signals should not exceed  $AV_{DD}$  or  $DV_{DD} + 0.5V$  or go below  $AV_{DD}$  or  $DV_{DD} - 0.5V$ . All pins have internal protection diodes that will protect them from short transients ( $< 100\mu s$ ) outside the supply range.

AGND and DGND pins are connected internally through the P-substrate. DC voltage differences between these pins will cause undesirable internal substrate currents.

The power supply ( $AV_{DD}$ ) and reference voltage ( $V_{RT}$  &  $V_{RB}$ ) pins should be decoupled with  $0.1\mu F$  and  $10\mu F$  capacitors to AGND, placed as close to the chip as possible.

The digital outputs should not drive long wires or buses. The

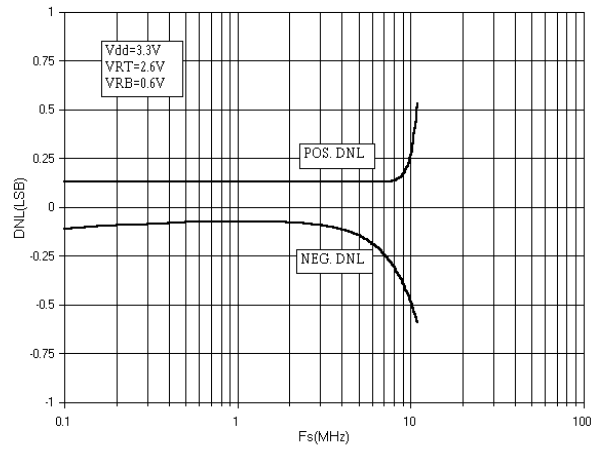
capacitive coupling and reflections will contribute noise to the conversion.

It is possible for the data valid delay ( $t_{DL}$ ) to be equal to or greater than the high pulse width of the sampling clock ( $t_{PWH}$ ). See Figure 1. This can cause timing related errors. For sample rates above 8 MSPS use only the rising edge of the sample clock (CLK) to latch data from the MP87L75 to other parts of the system.

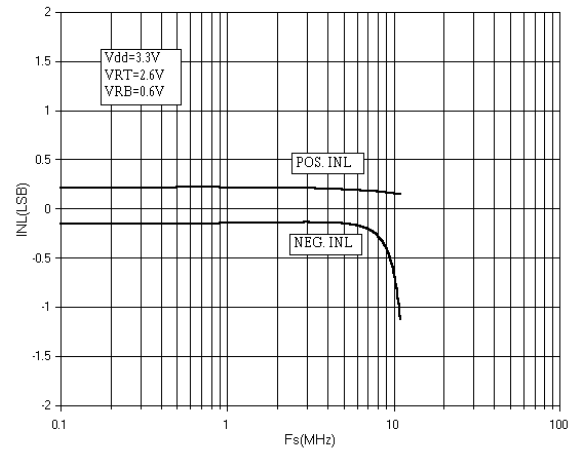
The reference can be biased internally by shorting  $V_{RT}$  to  $V_{RTS}$  and  $V_{RB}$  to  $V_{RBS}$ . This will generate  $0.36V$  at  $V_{RB}$  and  $1.56V$  at  $V_{RT}$  (see Figure 5.).

If the internal reference pins  $V_{RTS}$  and/or  $V_{RBS}$  are not used they should be left unconnected.

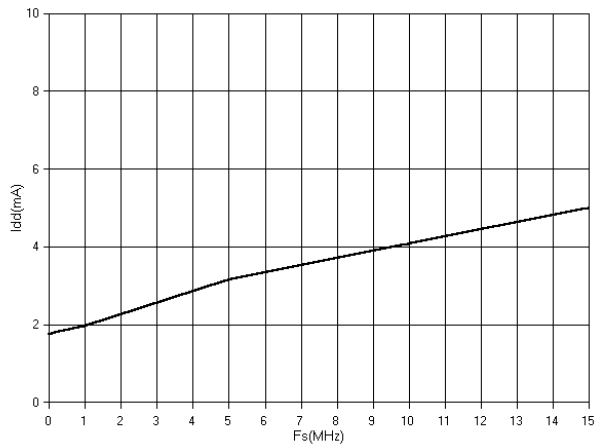
**PERFORMANCE CHARACTERISTICS**



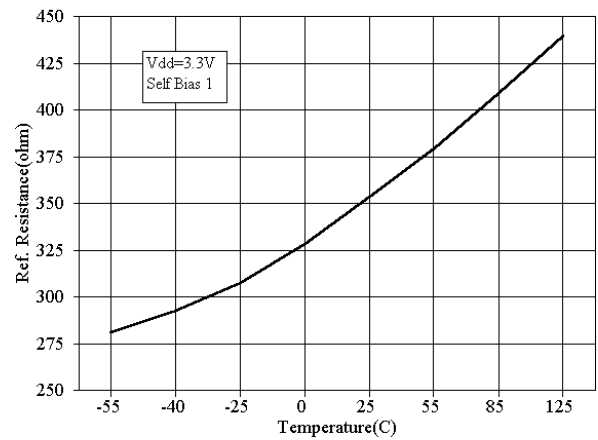
**Graph 1. DNL vs. Sampling Frequency**



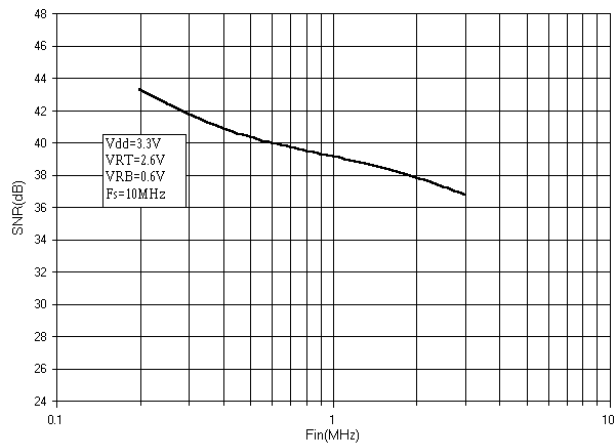
**Graph 2. INL vs. Sampling Frequency**



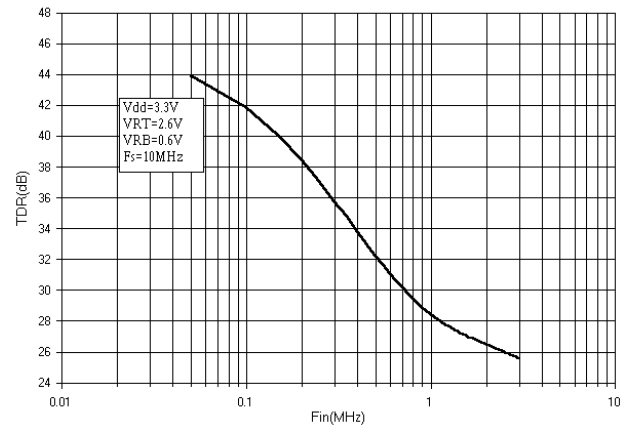
**Graph 3. Supply Current vs. Sampling Frequency**



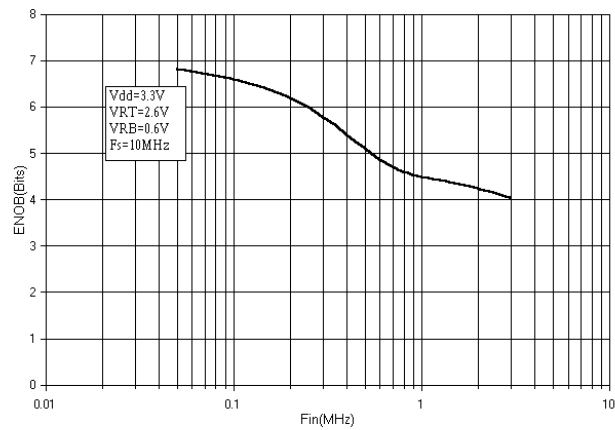
**Graph 4. Reference Resistance vs. Temperature**



**Graph 5. SNR vs. Input Frequency**



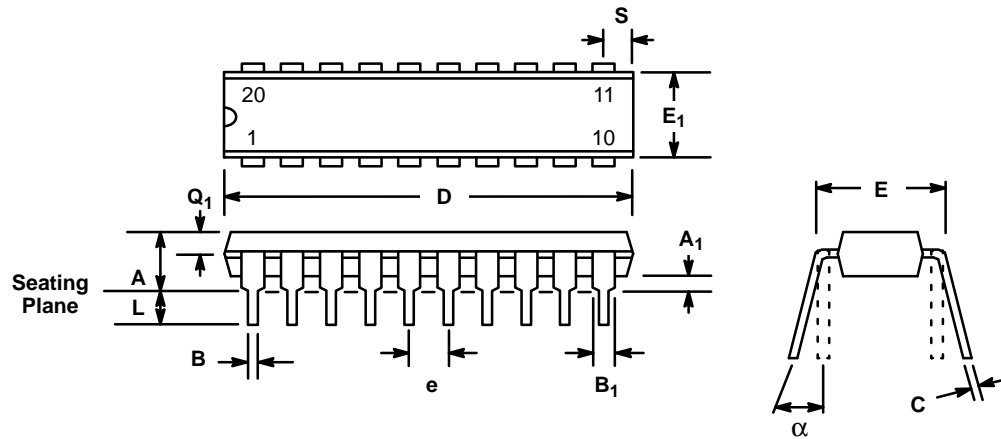
**Graph 6. SINAD vs. Input Frequency**



**Graph 7. ENOB vs. Input Frequency**



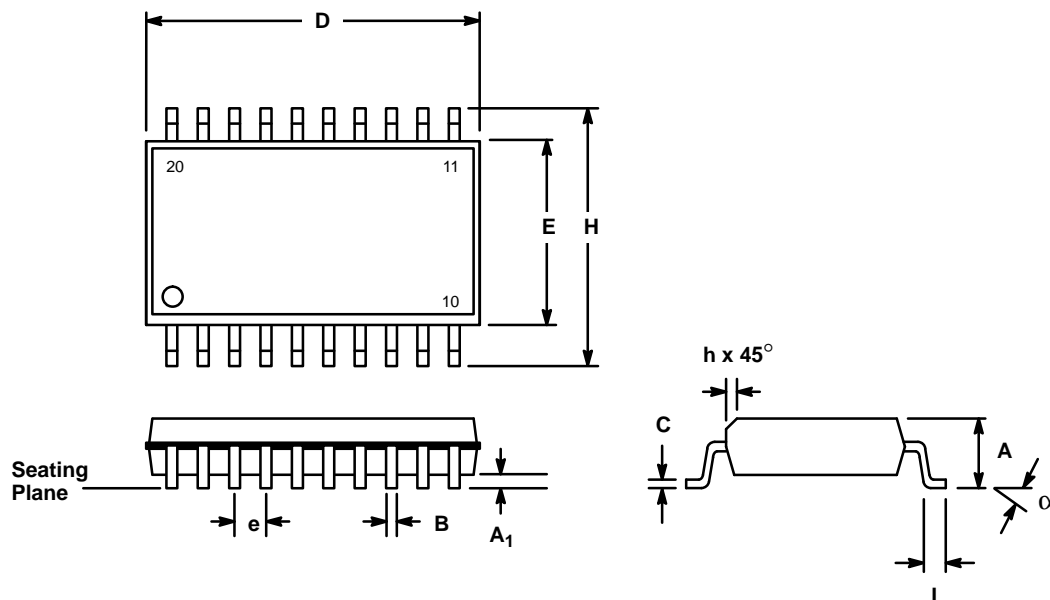
**20 LEAD PLASTIC DUAL-IN-LINE  
(300 MIL PDIP)  
N20**



SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	—	0.200	—	5.08
A <sub>1</sub>	0.015	—	0.38	—
B	0.014	0.023	0.356	0.584
B <sub>1</sub> (1)	0.038	0.065	0.965	1.65
C	0.008	0.015	0.203	0.381
D	0.945	1.060	24.0	26.92
E	0.295	0.325	7.49	8.26
E <sub>1</sub>	0.220	0.310	5.59	7.87
e	0.100 BSC		2.54 BSC	
L	0.115	0.150	2.92	3.81
α	0°	15°	0°	15°
Q <sub>1</sub>	0.055	0.070	1.40	1.78
S	0.040	0.080	1.02	2.03

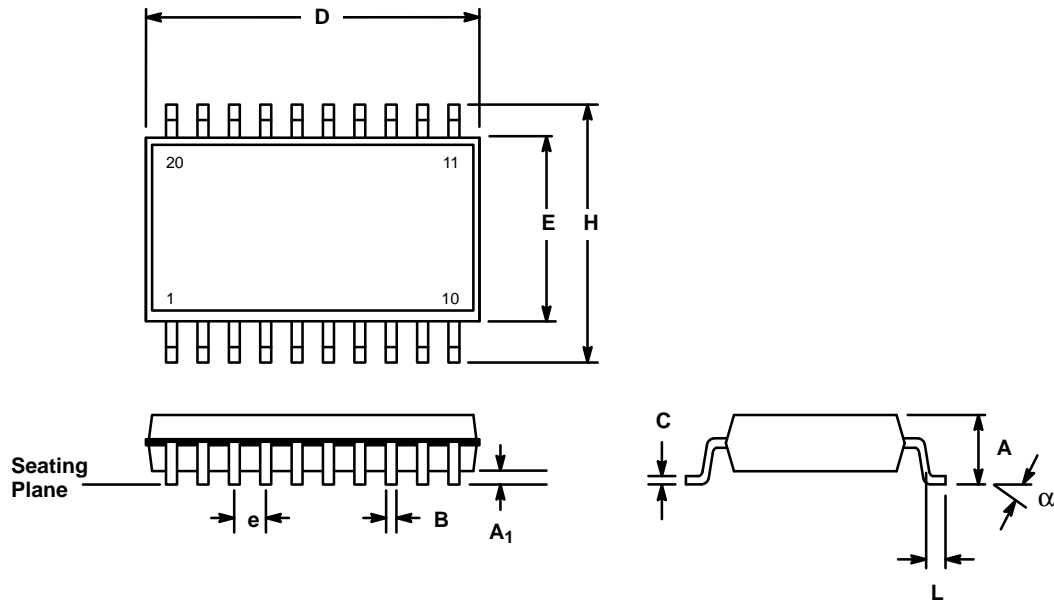
Note: (1) The minimum limit for dimensions B<sub>1</sub> may be 0.023" (0.58 mm) for all four corner leads only.

## 20 LEAD SMALL OUTLINE (300 MIL JEDEC SOIC) S20



SYMBOL	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.097	0.104	2.464	2.642
A <sub>1</sub>	0.0050	0.0115	0.127	0.292
B	0.014	0.019	0.356	0.483
C	0.0091	0.0125	0.231	0.318
D	0.500	0.510	12.70	12.95
E	0.292	0.299	7.42	7.59
e	0.050 BSC		1.27 BSC	
H	0.400	0.410	10.16	10.41
h	0.010	0.016	0.254	0.406
L	0.016	0.035	0.406	0.889
α	0°	8°	0°	8°

**20 LEAD SHRINK SMALL OUTLINE PACKAGE  
(SSOP)  
A20**



SYMBOL	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	1.73	2.05	0.068	0.081
A <sub>1</sub>	0.05	0.21	0.002	0.008
B	0.20	0.40	0.008	0.016
C	0.13	0.25	0.005	0.010
D	7.07	7.40	0.278	0.291
E	5.20	5.38	0.205	0.212
e	0.65 BSC		0.0256 BSC	
H	7.65	8.1	0.301	0.319
L	0.45	0.95	0.018	0.037
α	0°	8°	0°	8°

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